

# The Nature of Catastrophic Shorts in OLED Lighting



PennState



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## Catastrophic OLED panel failure

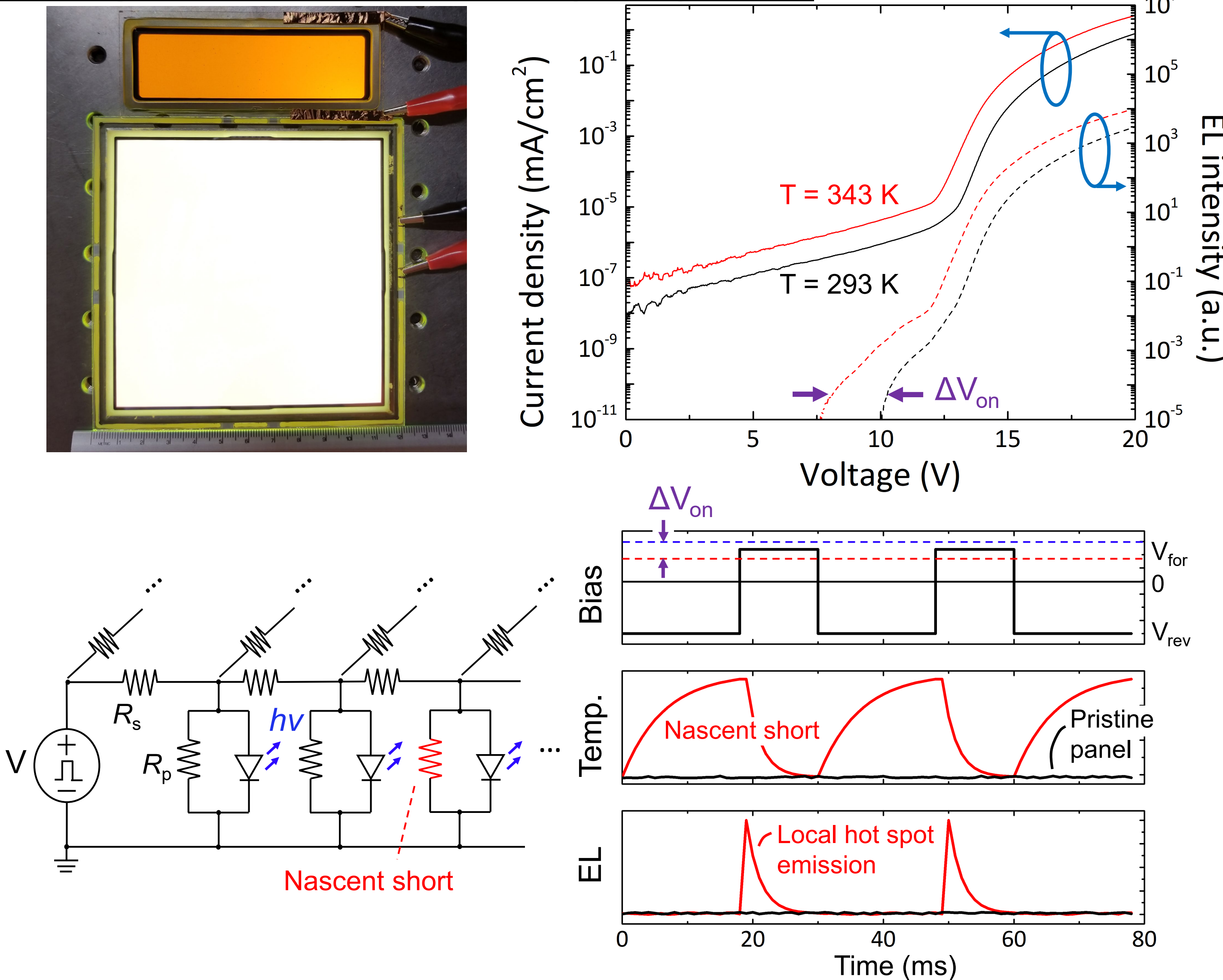
Prior to this work, catastrophic shorting was a major reliability challenge for OLED manufacturers.

- Origin unknown
- Unpredictable
- Lack of mitigation strategy

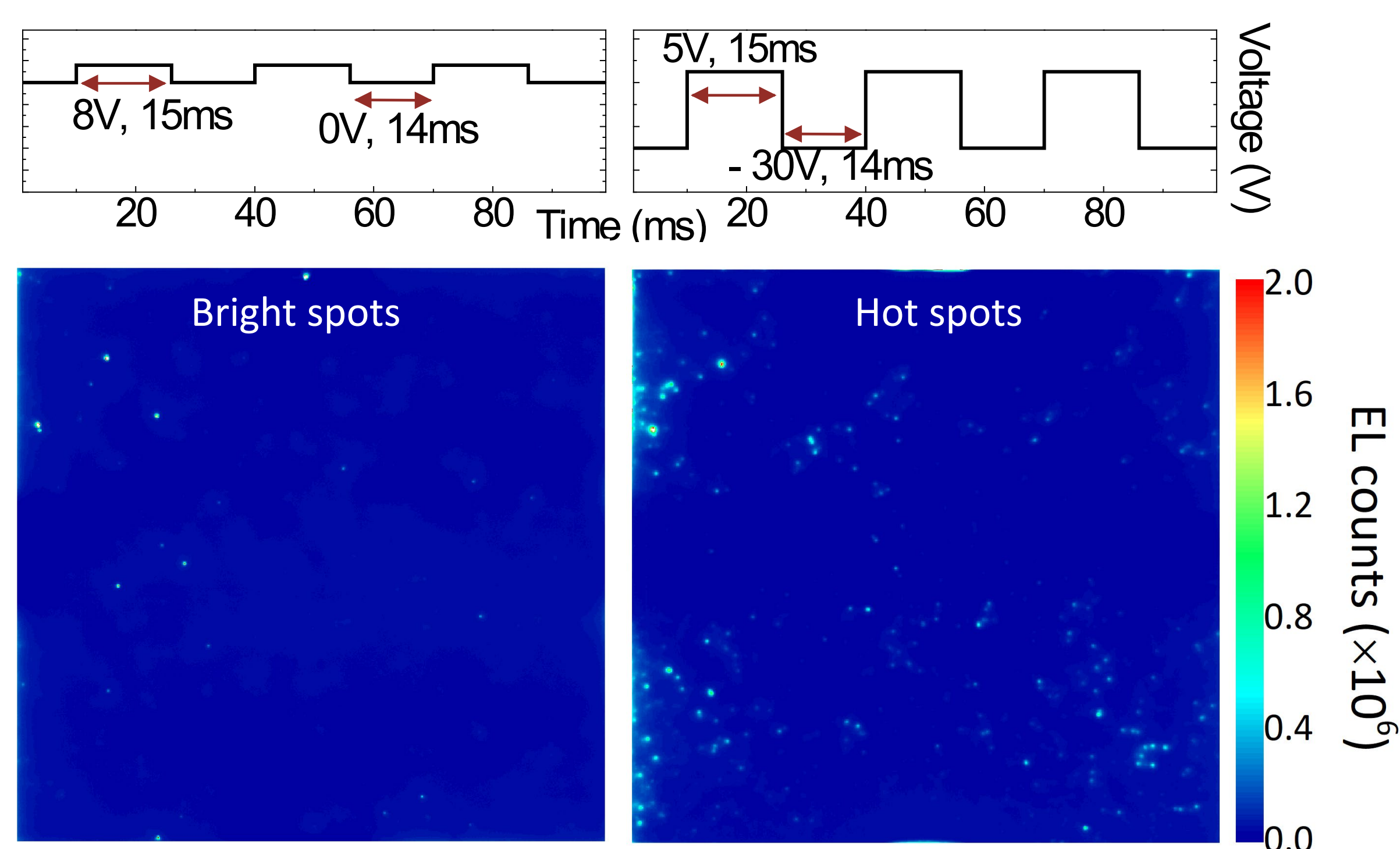


>>> Understanding the nature of shorts is critical

## Two general classes of defects



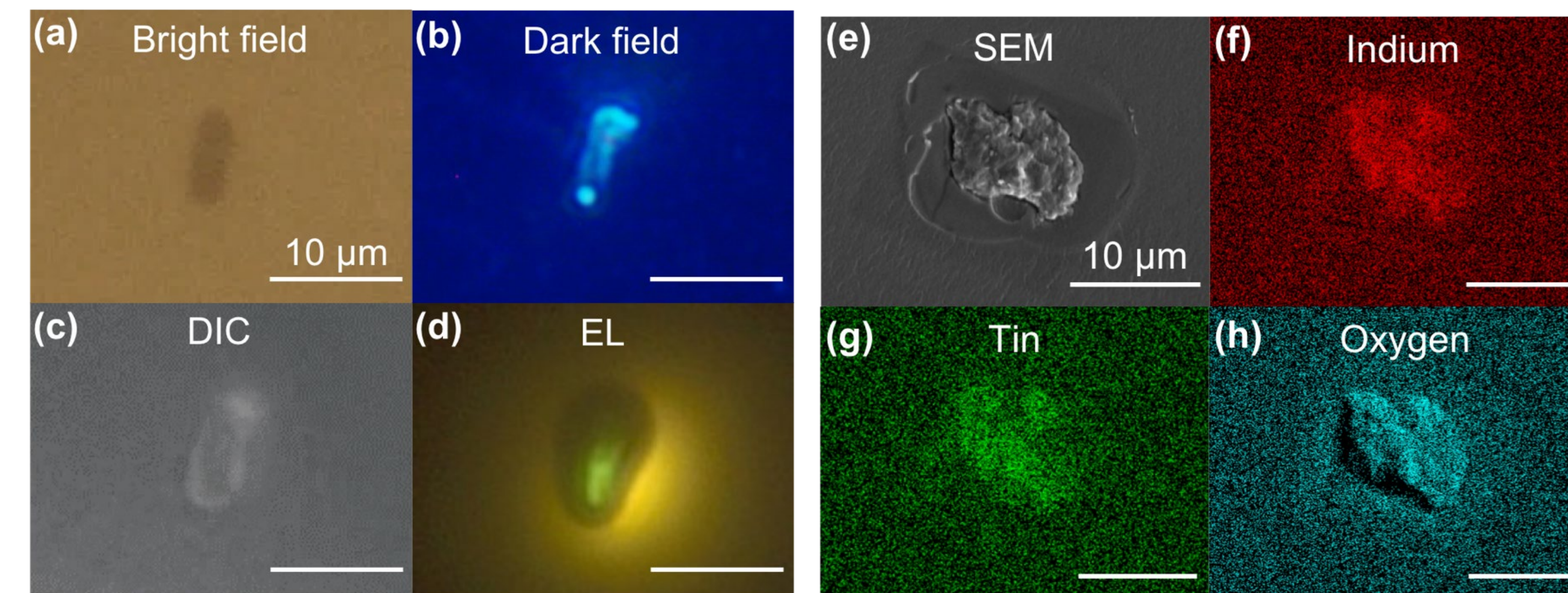
- Temperature-selective EL image



Previous work identified two classes of defects in commercial OLED lighting panels based on the electroluminescence drive condition.

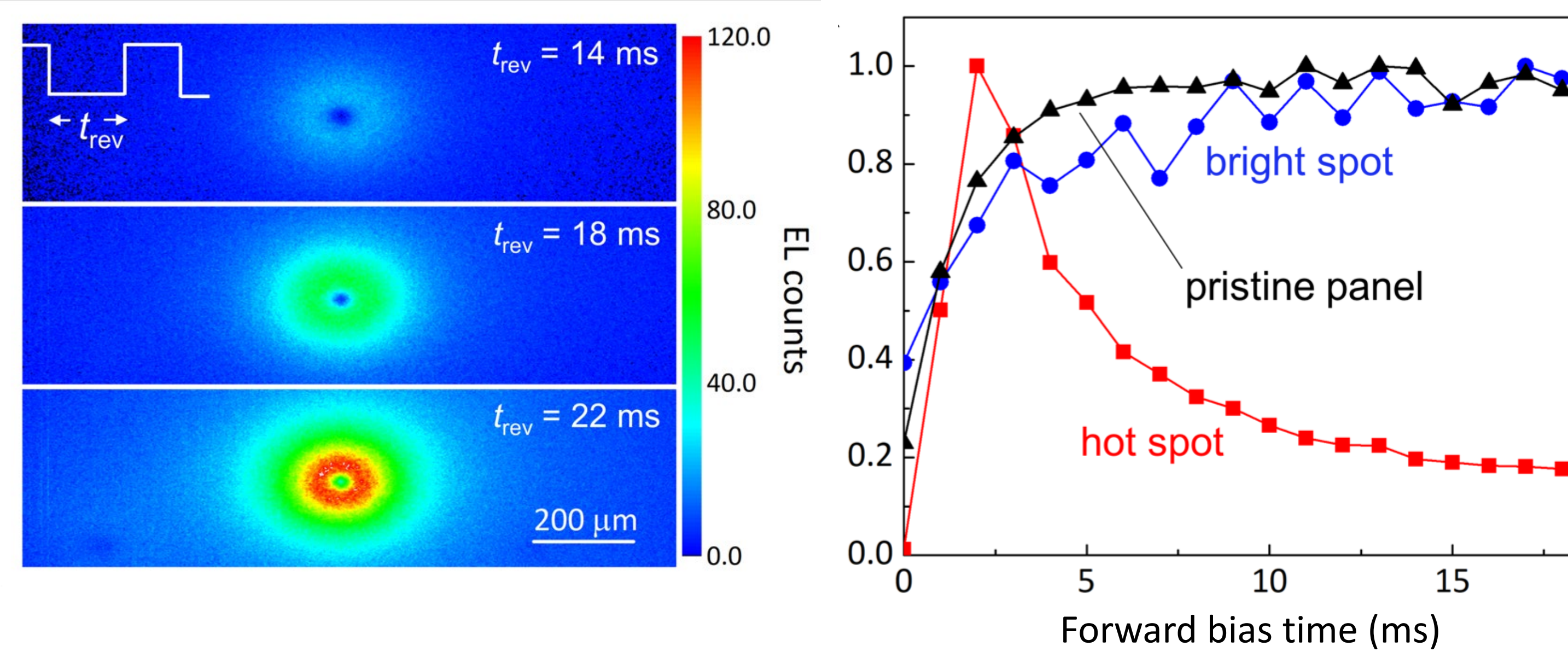
1. Bright spots: Local EL at subthreshold panel voltages.
  2. Hot spots: Observed under temperature-selective EL imaging.
- >> Hot spots & bright spots do not generally coincide

## Bright spot: micron-scale ITO particles

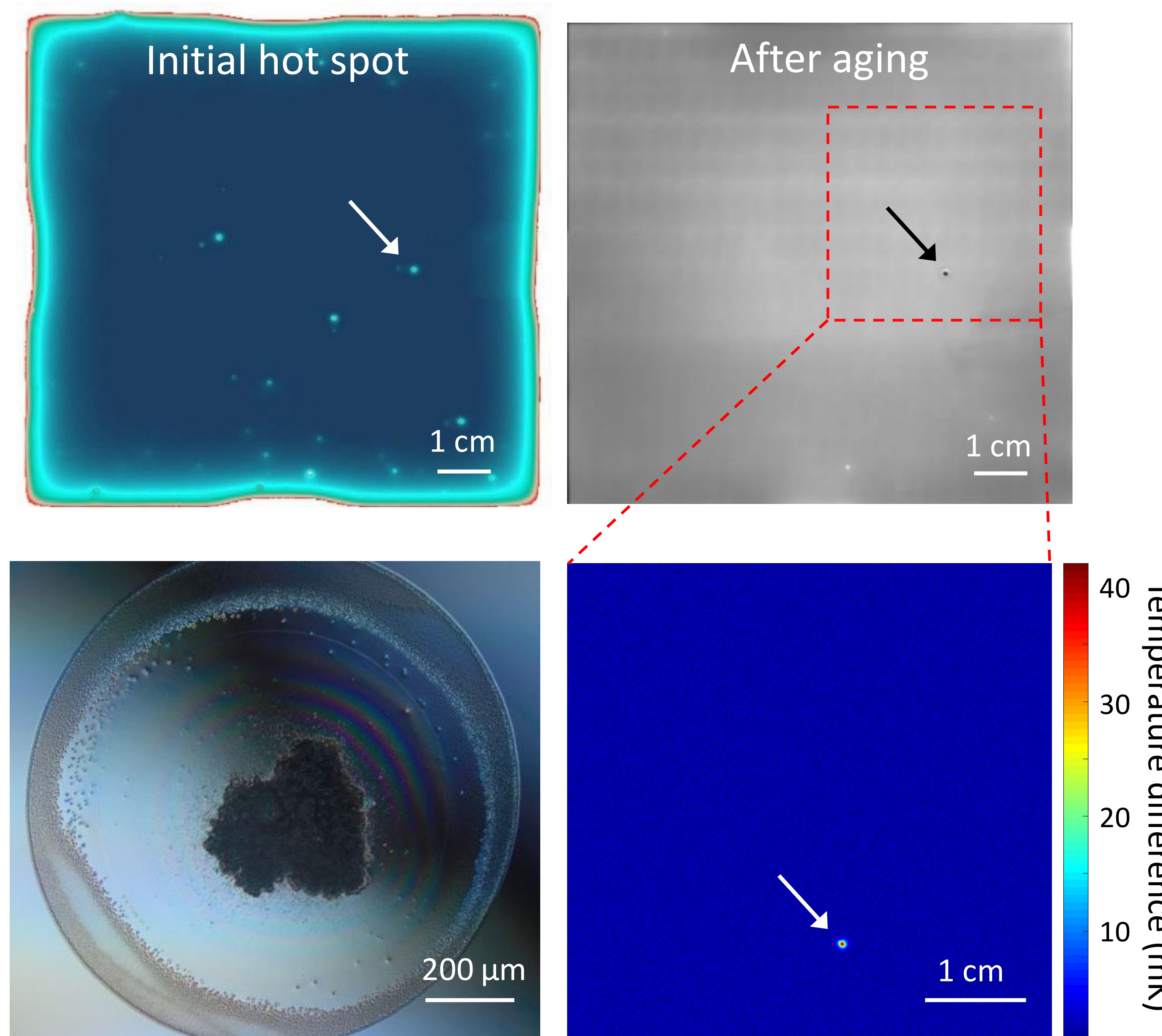


## Shorts originate from hot spots

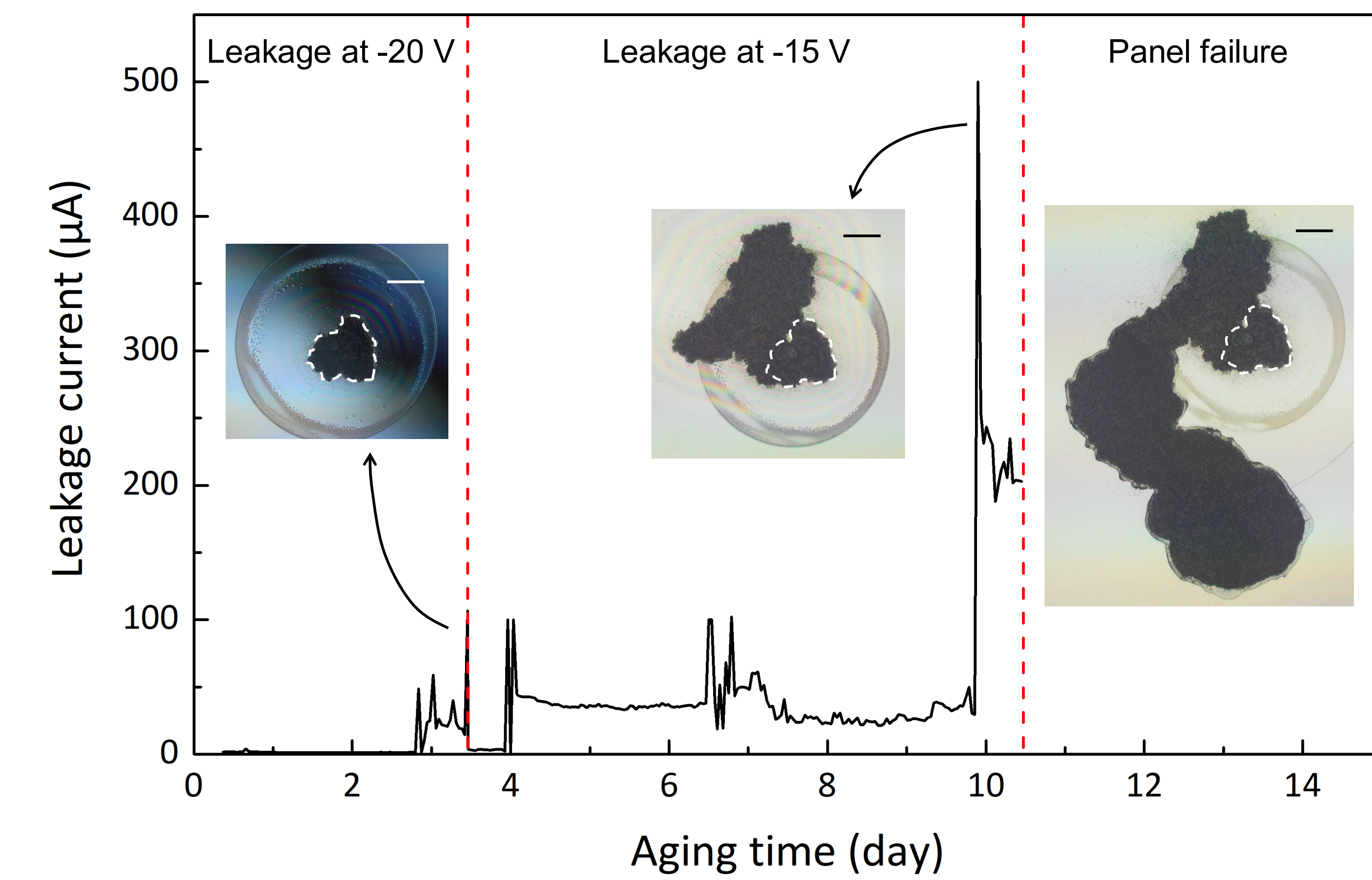
- Hot spot evolving with reverse bias duration



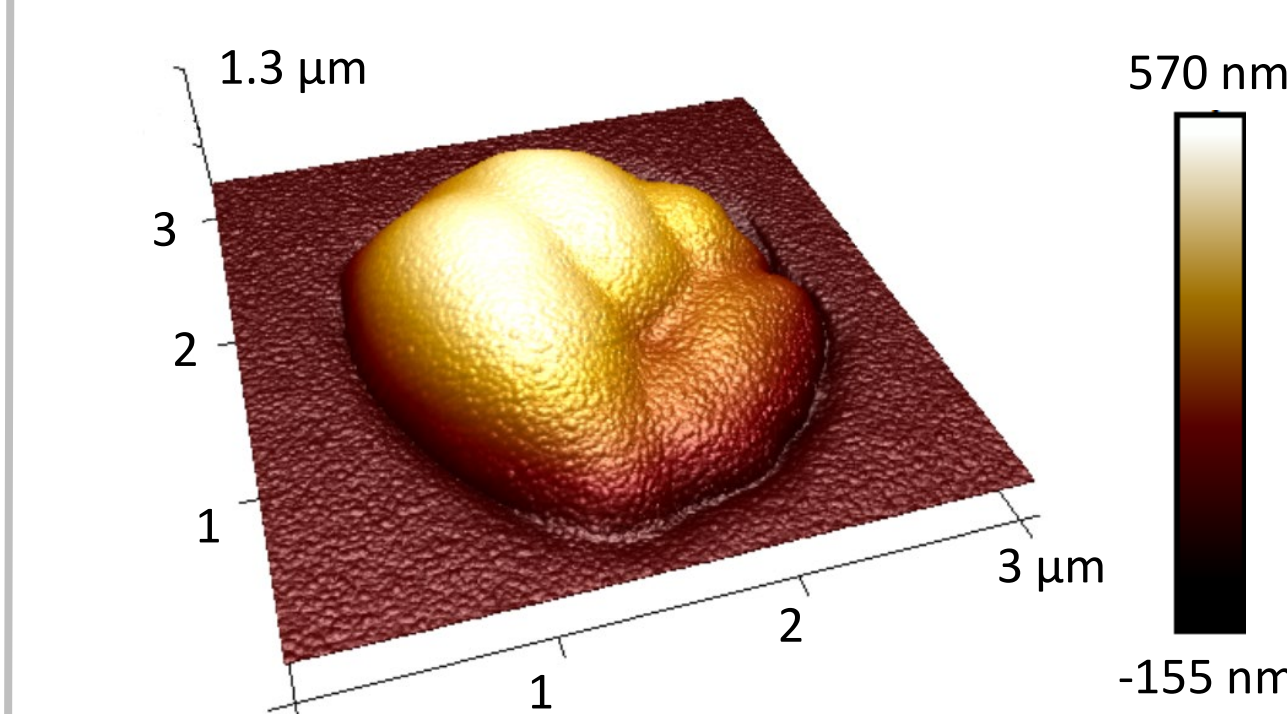
- Dark spot forming after accelerated fade testing on hot spot



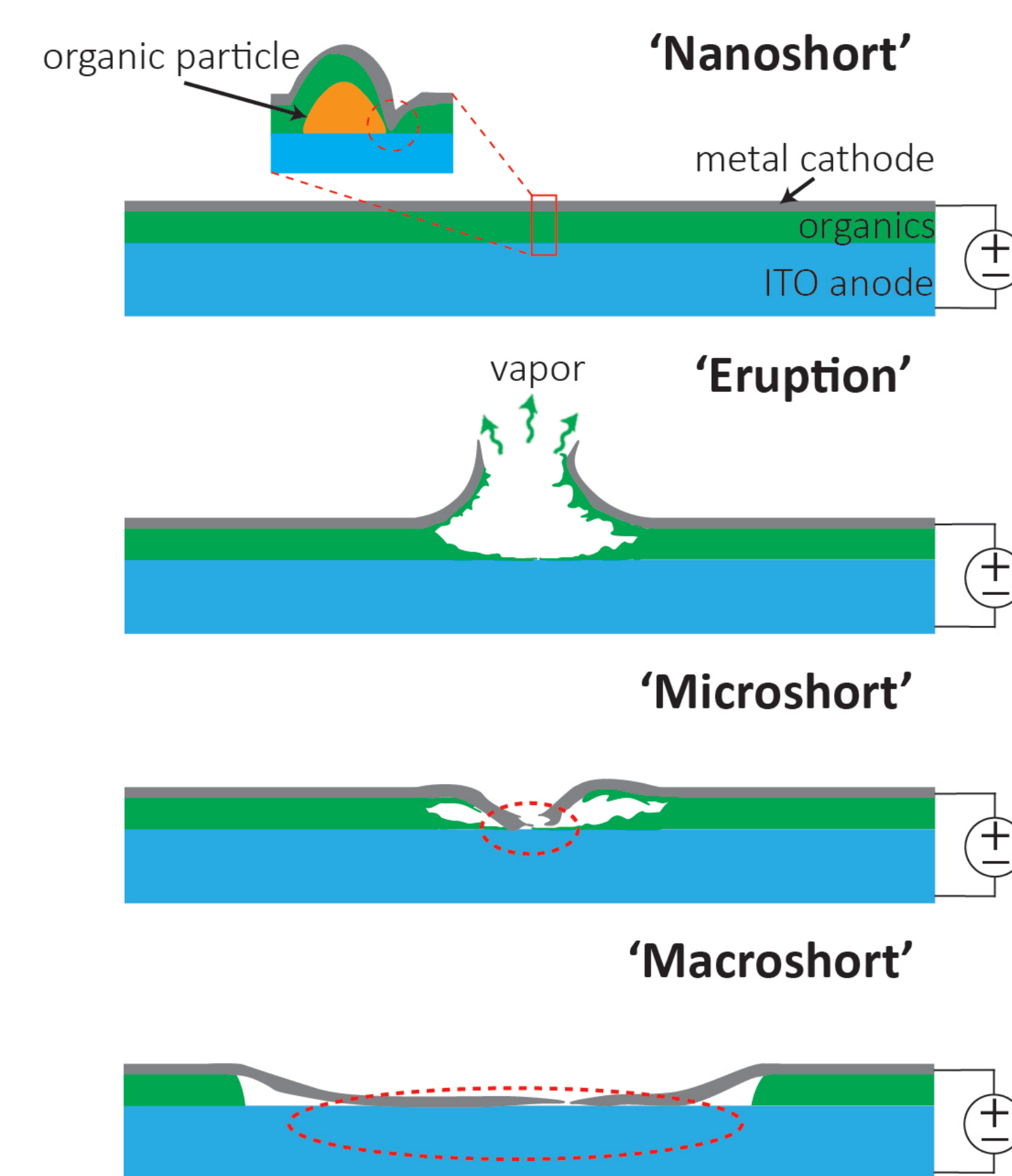
- Growth of the hot spot into the catastrophic short



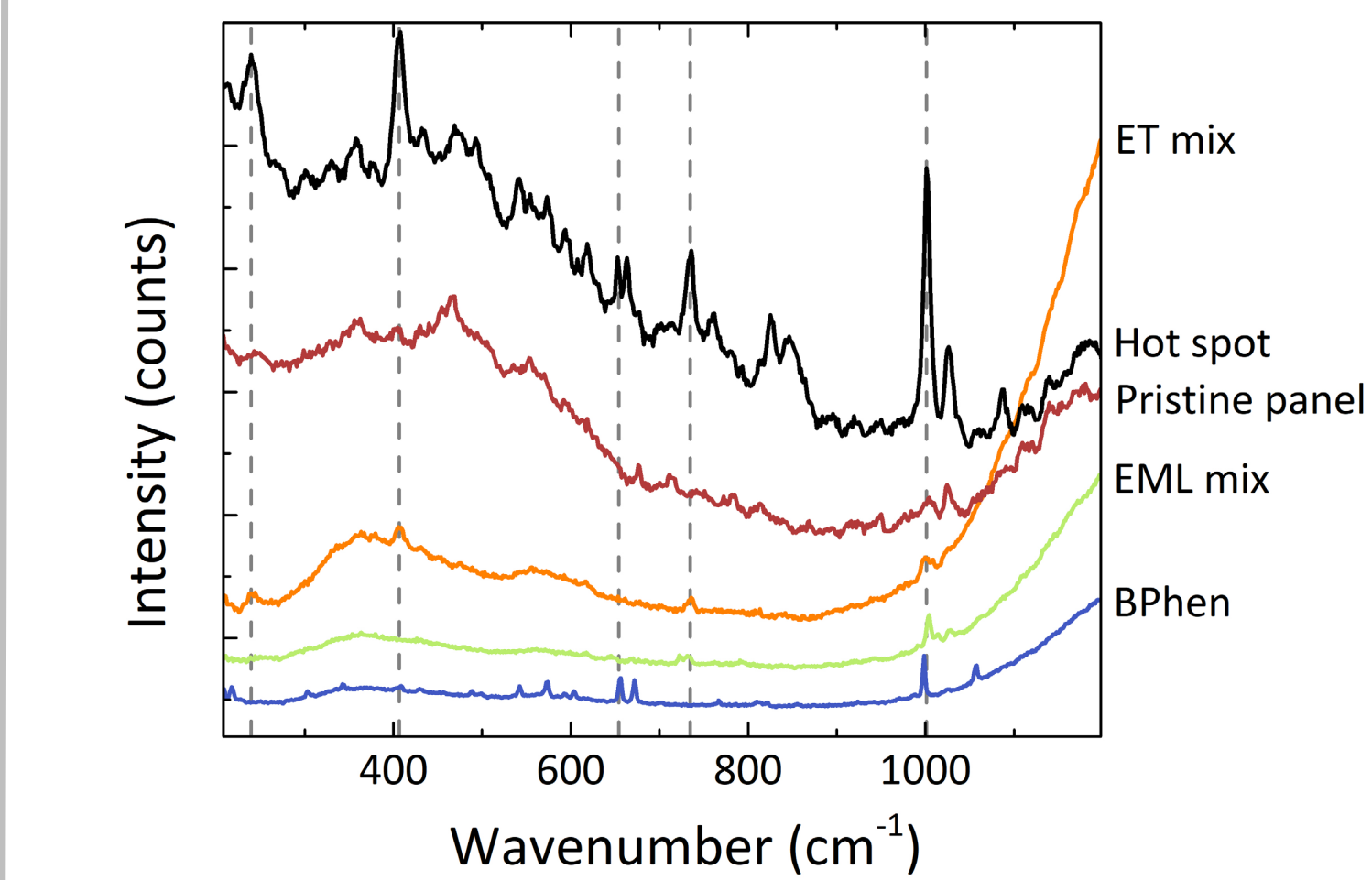
## Trench around the hot spot



## Key stages in the lifecycle of short



## Raman spectroscopy study



## Possible strategies

- Avoid shadowing
- Ultrathin dielectric layer
- Fuse-like layer

## Conclusions

- Two different classes of defects identified: 'Bright' spots and 'Hot' spots.
- Bright spots are associated with ITO particles and are not precursors of catastrophic shorts.
- Hot spots are associated with particulates in the organic layer stack and are precursors of catastrophic shorts.
- A model has been proposed for the growth of hot spots into catastrophic shorts.
- Proprietary new device architecture has been demonstrated to arrest growing shorts and eliminate catastrophic failure in production.